



# e.MMC Memory

## MTFC8GAM, MTFC16GAP, MTFC32GAP, MTFC64GAP, MTFC128GAP

### Features

MultiMediaCard (MMC) controller and NAND Flash

- JEDEC/MMC standard version 5.1-compliant (JEDEC Standard No. JESD84-B51)<sup>1</sup>
- $V_{CC}$ : 2.7–3.6V
- $V_{CCQ}$  (dual voltage): 1.70–1.95V; 2.7–3.6V
- Advanced 12-signal interface
- $\times 1$ ,  $\times 4$ , and  $\times 8$  I/Os, selectable by host
- e.MMC I/F boot frequency: 0 to 52 MHz
- e.MMC I/F clock frequency: 0 to 200 MHz
- HS200/HS400 mode
- Command classes: class 0 (basic); class 2 (block read); class 4 (block write); class 5 (erase); class 6 (write protection); class 7 (lock card)
- Command queue
- BKOPS control
- Temporary write protection
- Boot operation (high-speed boot)
- Sleep mode
- Replay-protected memory block (RPMB)
- Hardware reset signal
- Multiple partitions with enhanced attribute
- Permanent and power-on write protection
- High-priority interrupt (HPI)
- Data strobe pin
- Field firmware update (FFU)
- Device health report
- Sleep notification
- Background operation
- Reliable write
- Discard and sanitize
- Power-off notification
- Backward compatible with previous MMC
- ECC and block management implemented
- Automotive grade:
  - AEC-Q104
  - PPAP
- Retention AEC-Q100-005 compliant:
  - 10 years @55°C at 10% of PE
  - 5 years @55°C at maximum PE

| Options                                     | Marking |
|---|---------|
| • Density                                   |         |
| – 8GB                                       | 8G      |
| – 16GB                                      | 16G     |
| – 32GB                                      | 32G     |
| – 64GB                                      | 64G     |
| – 128GB                                     | 128G    |
| • NAND component                            |         |
| – 64Gb                                      | AM      |
| – 128Gb                                     | AP      |
| • Controller                                | AL      |
| • Packages – JEDEC-standard, RoHS-compliant |         |
| – 100-ball TBGA                             | NA      |
| – 153-ball TFBGA                            | BH      |
| – 153-ball TFBGA                            | NS      |
| • Operating temperature range               |         |
| – From -40°C to +85°C                       | AIT     |
| – From -40°C to +105°C                      | AAT     |

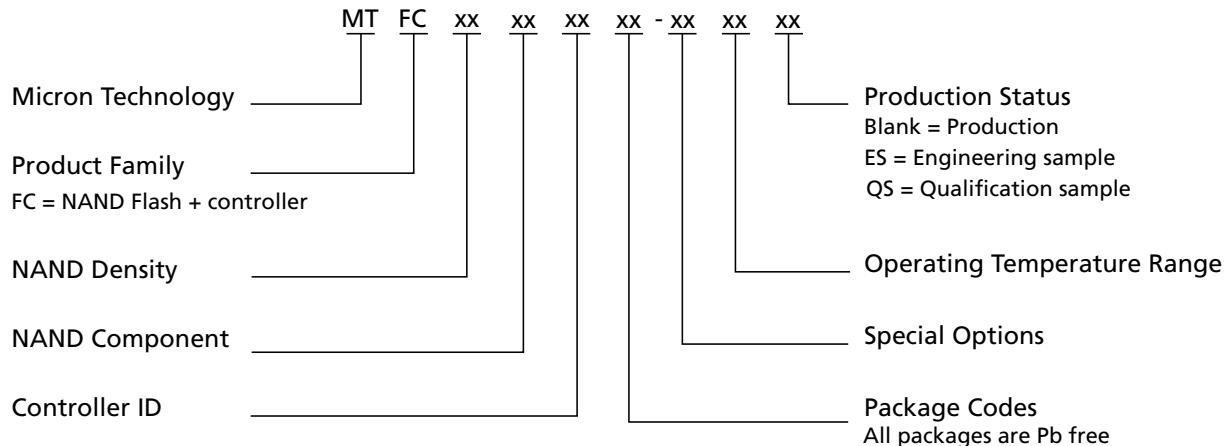
Note: 1. The JEDEC specification is available at [www.jedec.org/sites/default/files/docs/JESD84-B51.pdf](http://www.jedec.org/sites/default/files/docs/JESD84-B51.pdf).



## Part Numbering Information

Micron® e.MMC memory devices are available in different configurations and densities.

**Figure 1: e.MMC Part Numbering**



**Table 1: Ordering Information**

| Base Part Number   | Density | Package                                 | Shipping      |
|--------------------|---------|---|---------------|
| MTFC8GAMALBH-AIT   | 8GB     | 153-ball TFBGA<br>11.5mm × 13mm × 1.1mm | Tray          |
| MTFC8GAMALBH-AAT   |         |   | Tape and reel |
| MTFC8GAMALNA-AIT   | 8GB     | 100-ball TBGA<br>14mm × 18mm × 1.2mm    | Tray          |
| MTFC8GAMALNA-AAT   |         |   | Tape and reel |
| MTFC16GAPALBH-AIT  | 16GB    | 153-ball TFBGA<br>11.5mm × 13mm × 1.1mm | Tray          |
| MTFC16GAPALBH-AAT  |         |   | Tape and reel |
| MTFC16GAPALNA-AIT  | 16GB    | 100-ball TBGA<br>14mm × 18mm × 1.2mm    | Tray          |
| MTFC16GAPALNA-AAT  |         |   | Tape and reel |
| MTFC32GAPALBH-AIT  | 32GB    | 153-ball TFBGA<br>11.5mm × 13mm × 1.1mm | Tray          |
| MTFC32GAPALBH-AAT  |         |   | Tape and reel |
| MTFC32GAPALNA-AIT  | 32GB    | 100-ball TBGA<br>14mm × 18mm × 1.2mm    | Tray          |
| MTFC32GAPALNA-AAT  |         |   | Tape and reel |
| MTFC64GAPALBH-AIT  | 64GB    | 153-ball TFBGA<br>11.5mm × 13mm × 1.1mm | Tray          |
| MTFC64GAPALBH-AAT  |         |   | Tape and reel |
| MTFC64GAPALNA-AIT  | 64GB    | 100-ball TBGA<br>14mm × 18mm × 1.2mm    | Tray          |
| MTFC64GAPALNA-AAT  |         |   | Tape and reel |
| MTFC128GAPALNS-AIT | 128GB   | 153-ball TFBGA<br>11.5mm × 13mm × 1.2mm | Tray          |
| MTFC128GAPALNS-AAT |         |   | Tape and reel |
| MTFC128GAPALNA-AIT | 128GB   | 100-ball TBGA<br>14mm × 18mm × 1.2mm    | Tray          |
| MTFC128GAPALNA-AAT |         |   | Tape and reel |



## Device Marking

Due to the size of the package, the Micron-standard part number is not printed on the top of the device. Instead, an abbreviated device mark consisting of a 5-digit alphanumeric code is used. The abbreviated device marks are cross-referenced to the Micron part numbers at the FBGA Part Marking Decoder site: [www.micron.com/decoder](http://www.micron.com/decoder).

## e.MMC Performance

Performance in the following tables are retrieved with these conditions: Bus in x8 I/O; Temperature 25°C; Sequential access of 512KB chunk; Cache ON (write), Command queueing enabled with queue depth 8 commands in HS400.

Additional performance data, such as system performance on a specific application board, is provided in a separate document upon customer request.

**Table 2: HS400 Performance**

| Condition        | Typical Values |      |             | Unit |
|------------------|----------------|------|-------------|------|
|                  | 8GB            | 16GB | 32/64/128GB |      |
| Sequential write | 40             | 60   | 120         | MB/s |
| Sequential read  | 280            | 320  | 320         | MB/s |

**Table 3: HS200 Performance**

| Condition        | Typical Values |      |             | Unit |
|------------------|----------------|------|-------------|------|
|                  | 8GB            | 16GB | 32/64/128GB |      |
| Sequential write | 40             | 60   | 100         | MB/s |
| Sequential read  | 180            | 180  | 180         | MB/s |

## e.MMC Current Consumption

Current consumption in the following tables are retrieved with these conditions: Bus in x8 I/O;  $V_{CC} = 3.6V$  and  $V_{CCQ} = 1.95V$ ; Temperature 25°C; Measurements done as average RMS current consumption;  $I_{CCQ}$  in READ operation measurements with tester load disconnected.

**Table 4: HS400 Current Consumption**

| Condition          | Typical Values ( $I_{CC}/I_{CCQ}$ ) |         |         |         |         | Unit |
|--------------------|-------------------------------------|---------|---------|---------|---------|------|
|                    | 8GB                                 | 16GB    | 32GB    | 64GB    | 128GB   |      |
| Write <sup>1</sup> | 60/90                               | 60/90   | 110/90  | 110/90  | 110/90  | mA   |
| Read <sup>1</sup>  | 100/140                             | 120/140 | 120/140 | 120/140 | 150/140 | mA   |
| Sleep              | 0/100                               | 0/100   | 0/100   | 0/100   | 0/100   | µA   |
| Auto standby       | 60/110                              | 80/110  | 80/110  | 120/110 | 250/110 | µA   |

Note: 1. Command queueing enabled with queue depth 8 commands.

**Table 5: HS200 Current Consumption**

| <b>Condition</b> | <b>Typical Values (I<sub>CC</sub>/I<sub>CCQ</sub>)</b> |             |             |             |              | <b>Unit</b> |
|------------------|--|-------------|-------------|-------------|--------------|-------------|
|                  | <b>8GB</b>   | <b>16GB</b> | <b>32GB</b> | <b>64GB</b> | <b>128GB</b> |             |
| Write            | 50/80  | 50/80       | 100/80      | 100/80      | 100/80       | mA          |
| Read             | 70/110   | 80/110      | 80/110      | 80/110      | 90/110       | mA          |
| Sleep            | 0/100  | 0/100       | 0/100       | 0/100       | 0/100        | µA          |
| Auto standby     | 60/110   | 80/110      | 80/110      | 120/110     | 250/110      | µA          |



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## General Description

Micron e.MMC is a communication and mass data storage device that includes a MultiMediaCard (MMC) interface, a NAND Flash component, and a controller on an advanced 12-signal bus, which is compliant with the MMC system specification. Its cost per bit, small package sizes, and high reliability make it an ideal choice for automotive applications, including information and entertainment, navigation tools, advanced driving assistance systems, and a variety of other industrial and portable products.

The nonvolatile e.MMC draws no power to maintain stored data, delivers high performance across a wide range of operating temperatures, and resists shock and vibration disruption.



## Signal Descriptions

**Table 6: Signal Descriptions**

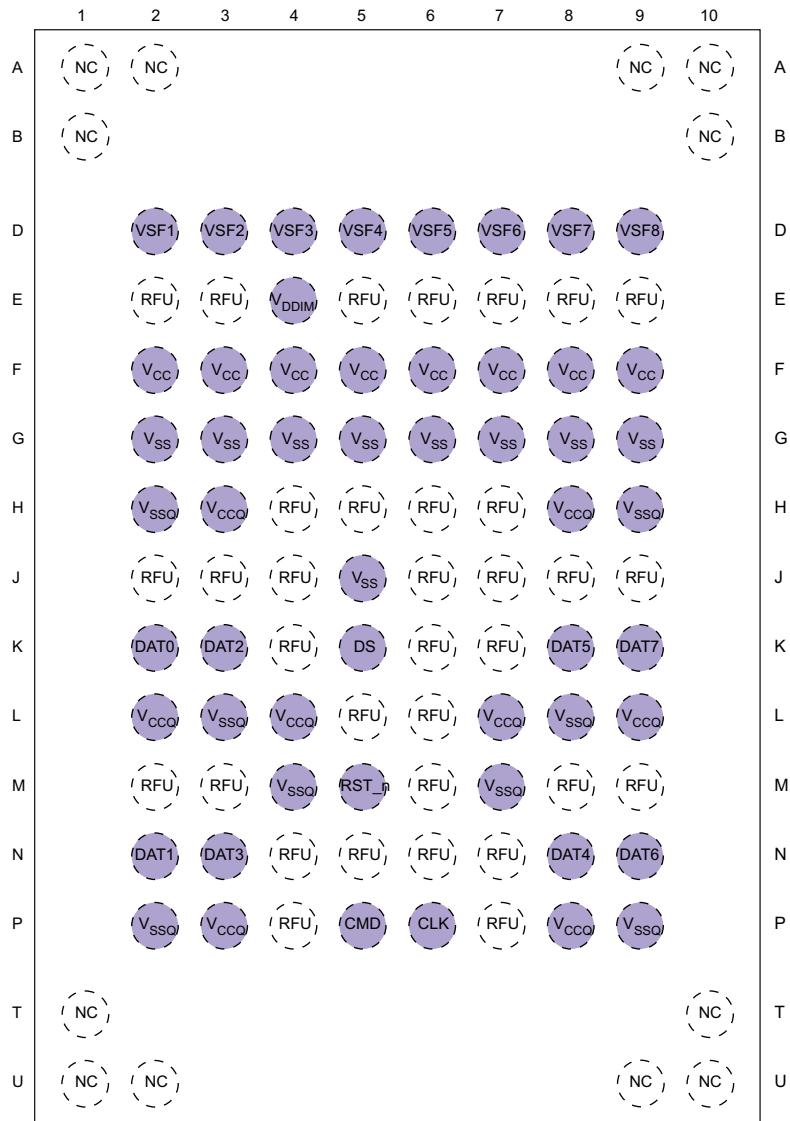
| Symbol                        | Type         | Description  |
|-------------------------------|--------------|--|
| CLK                           | Input        | Clock: Each cycle of the clock directs a transfer on the command line and on the data line(s). The frequency can vary between the minimum and the maximum clock frequency.   |
| RST_n                         | Input        | Reset: The RST_n signal is used by the host for resetting the device, moving the device to the pre-idle state. By default, the RST_n signal is temporarily disabled in the device. The host must set ECSD register byte 162, bits[1:0] to 0x1 to enable this functionality before the host can use it.   |
| CMD                           | I/O          | Command: This signal is a bidirectional command channel used for command and response transfers. The CMD signal has two bus modes: open-drain mode and push-pull mode (see Operating Modes). Commands are sent from the MMC host to the device, and responses are sent from the device to the host.  |
| DAT[7:0]                      | I/O          | Data I/O: These are bidirectional data signals. The DAT signals operate in push-pull mode. By default, after power-on or assertion of the RST_n signal, only DAT0 is used for data transfer. The MMC controller can configure a wider data bus for data transfer either using DAT[3:0] (4-bit mode) or DAT[7:0] (8-bit mode). e-MMC includes internal pull-up resistors for data lines DAT[7:1]. Immediately after entering the 4-bit mode, the device disconnects the internal pull-up resistors on the DAT[3:1] lines. Upon entering the 8-bit mode, the device disconnects the internal pull-ups on the DAT[7:1] lines. |
| DS                            | Output       | Data strobe: Generated by the device and used for data output and CRC status response output in HS400 mode. The frequency of this signal follows the frequency of CLK. For data output, each cycle of this signal directs two bits transfer (2x) on the data, one bit for the positive edge and the other bit for the negative edge. For CRC status response output, the CRC status is latched on the positive edge only, and is "Don't Care" on the negative edge.  |
| VSF[7:1]                      | Input/output | Vendor specific function: VSF1, VSF2, VSF3, VSF4, VSF5, VSF6, and VSF7 are internally connected. VSF[7:1] must be left floating.   |
| V <sub>CC</sub>               | Supply       | V <sub>CC</sub> : NAND interface (I/F) I/O and NAND Flash power supply.  |
| V <sub>CCQ</sub>              | Supply       | V <sub>CCQ</sub> : e-MMC controller core and e-MMC I/F I/O power supply.   |
| V <sub>SS</sub> <sup>1</sup>  | Supply       | V <sub>SS</sub> : NAND I/F I/O and NAND Flash ground connection.   |
| V <sub>SSQ</sub> <sup>1</sup> | Supply       | V <sub>SSQ</sub> : e-MMC controller core and e-MMC I/F ground connection.  |
| V <sub>DDIM</sub>             |              | Internal voltage node: At least a 0.1 $\mu$ F capacitor is required to connect V <sub>DDIM</sub> to ground. A 1 $\mu$ F capacitor is recommended; Do not tie to supply voltage or ground.  |
| NC                            | -            | No connect: No internal connection is present.   |
| RFU                           | -            | Reserved for future use: No internal connection is present; Leave it floating externally.  |

Note: 1. V<sub>SS</sub> and V<sub>SSQ</sub> are connected internally.



## 100-Ball Signal Assignments

**Figure 2: 100 Ball (Top View, Ball Down)**



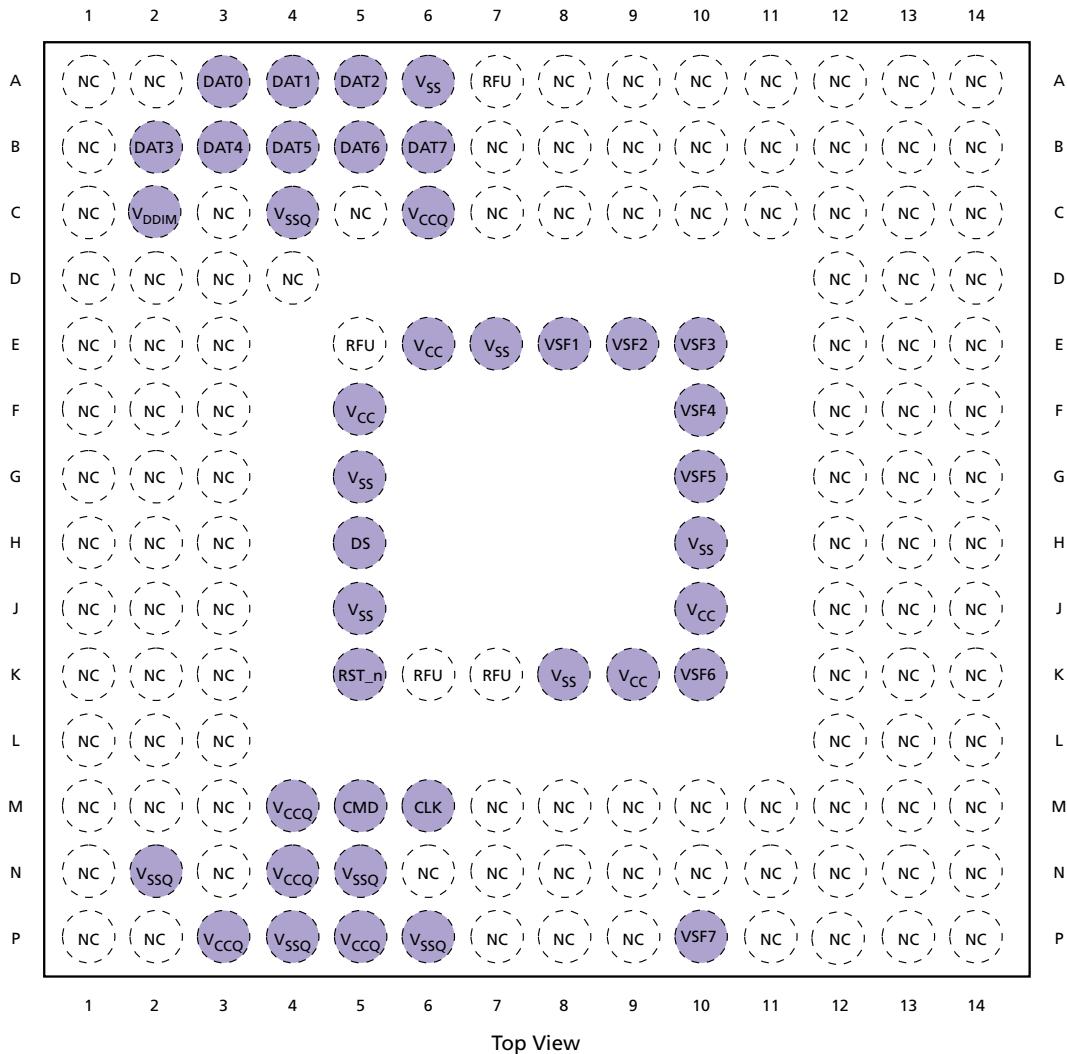
Notes:

1. Connect a 1 $\mu$ F decoupling capacitor from V<sub>DDIM</sub> to ground.
2. Some previous versions of the JEDEC product or mechanical specification had defined reserved for future use (RFU) balls as no connect (NC) balls. NC balls assigned in the previous specifications could have been connected to ground on the system board. To enable new feature introduction, some of these balls are assigned as RFU in the v4.4 mechanical specification. Any new PCB footprint implementations should use the new ball assignments and leave the RFU balls floating on the system board.
3. V<sub>CC</sub>, V<sub>CCQ</sub>, V<sub>SS</sub>, and V<sub>SSQ</sub> balls must all be connected on the system board.



## 153-Ball Signal Assignments

**Figure 3: 153 Ball (Top View, Ball Down)**

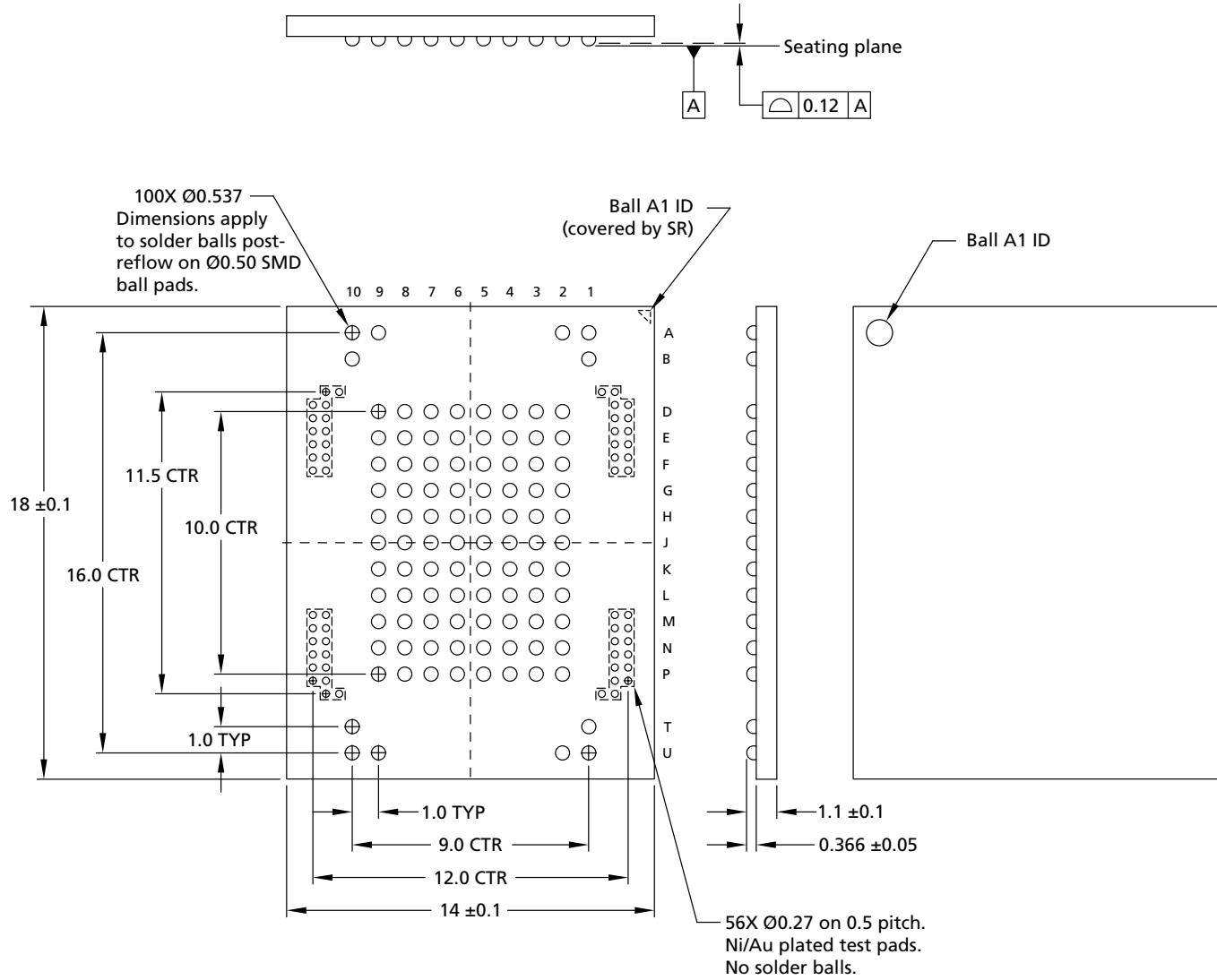


Notes:

1. Some previous versions of the JEDEC product or mechanical specification had defined reserved for future use (RFU) balls as no connect (NC) balls. NC balls assigned in the previous specifications could have been connected to ground on the system board. To enable new feature introduction, some of these balls are assigned as RFU in the v4.4 mechanical specification. Any new PCB footprint implementations should use the new ball assignments and leave the RFU balls floating on the system board.
2. **V<sub>CC</sub>**, **V<sub>CCQ</sub>**, **V<sub>SS</sub>**, and **V<sub>SSQ</sub>** balls must all be connected on the system board.

## Package Dimensions

**Figure 4: 100-Ball TBGA – 14mm x 18mm x 1.2mm (Package Code NA)**

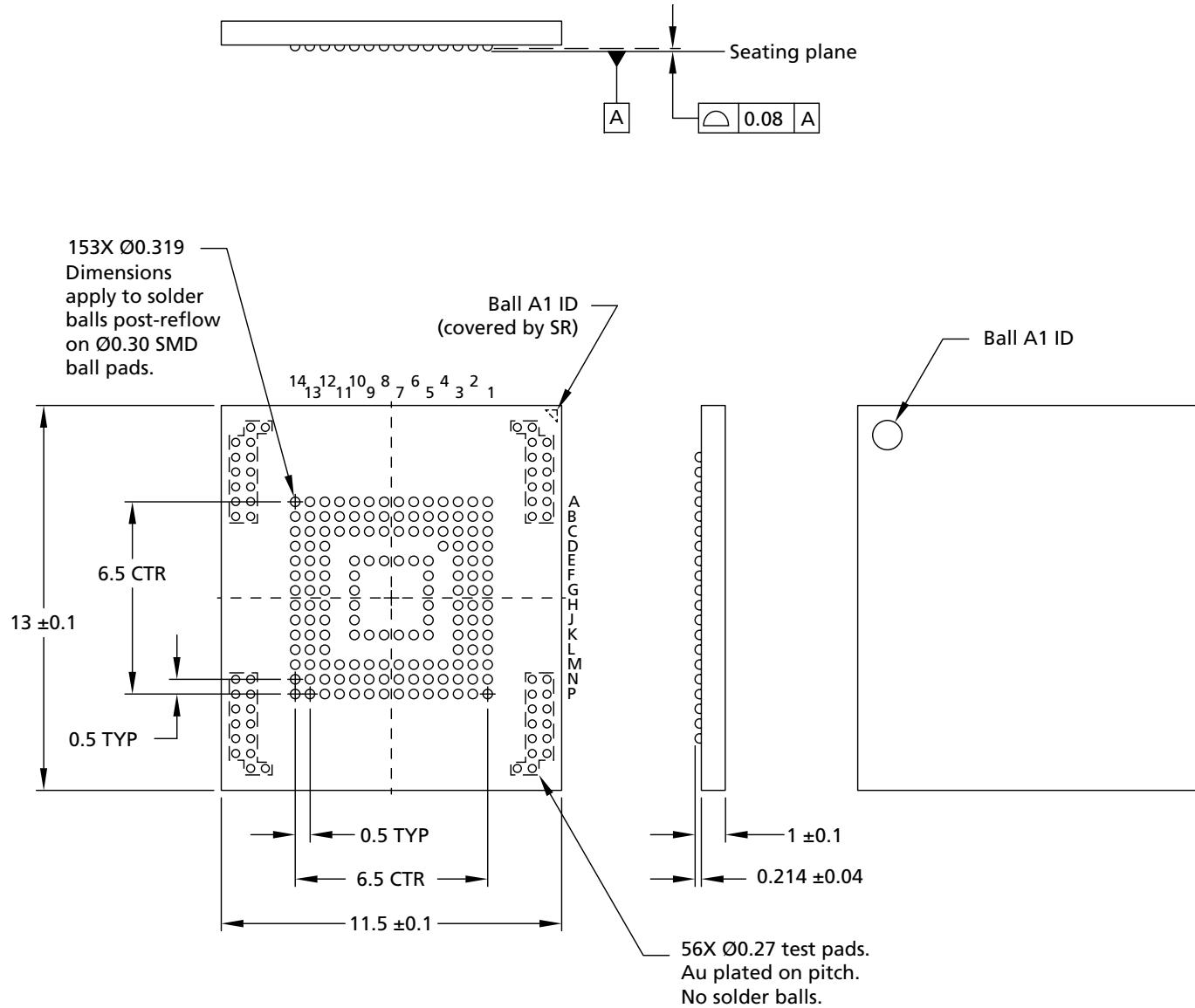


Notes: 1. Dimensions are in millimeters.  
2. Solder ball composition: SAC302 with NiAu pads (96.8% Sn, 3.0% Ag, 0.2% Cu)



## 8GB, 16GB, 32GB, 64GB, 128GB: e.MMC (Automotive) Package Dimensions

Figure 5: 153-Ball TFBGA – 11.5mm x 13.0mm x 1.1mm (Package Code BH)



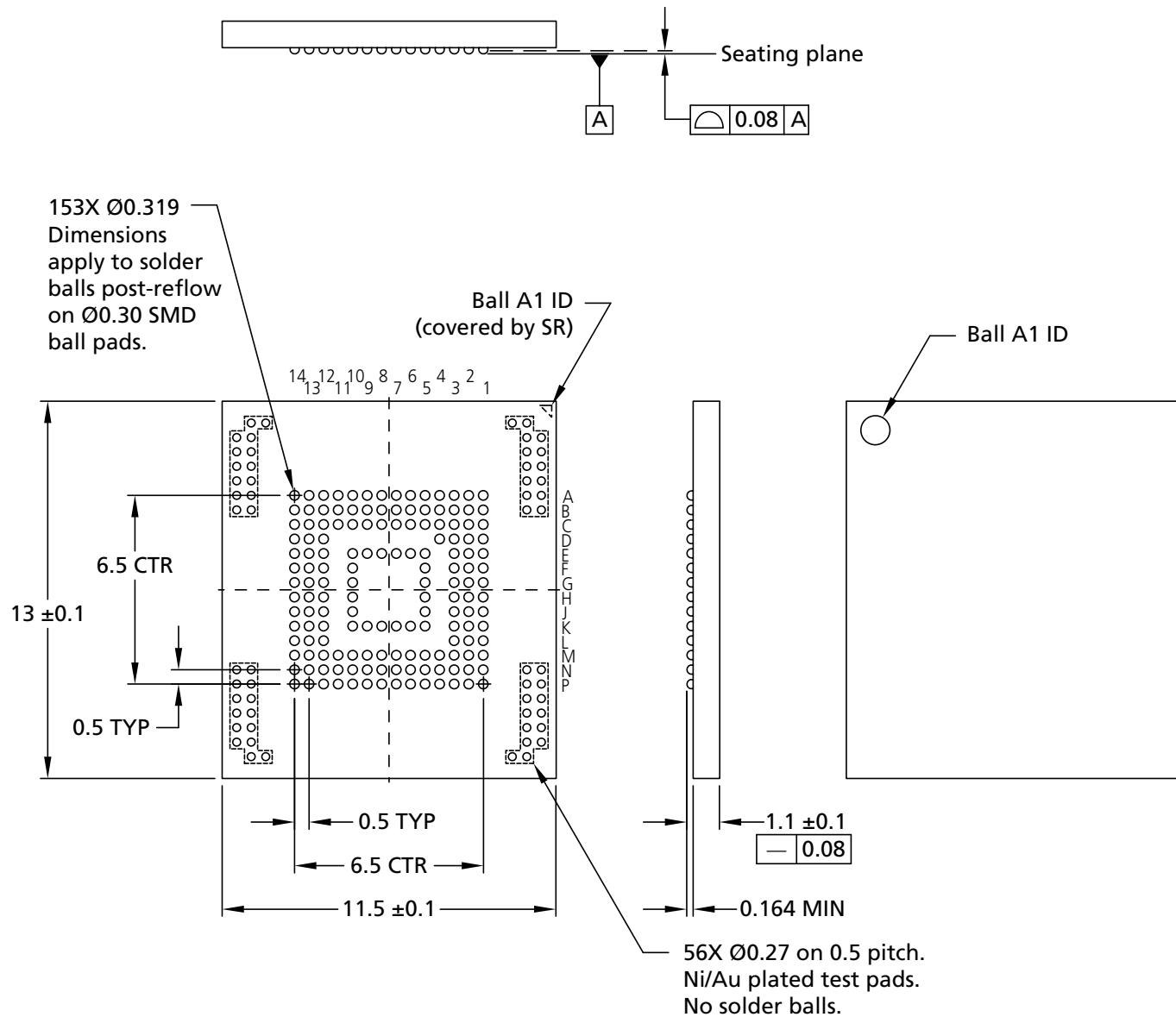
Notes: 1. Dimensions are in millimeters.

2. Solder ball composition: SAC302 with NiAu pads (96.8% Sn, 3.0% Ag, 0.2% Cu)



## 8GB, 16GB, 32GB, 64GB, 128GB: e.MMC (Automotive) Package Dimensions

Figure 6: 153-Ball TFBGA – 11.5mm x 13.0mm x 1.2mm (Package Code NS)

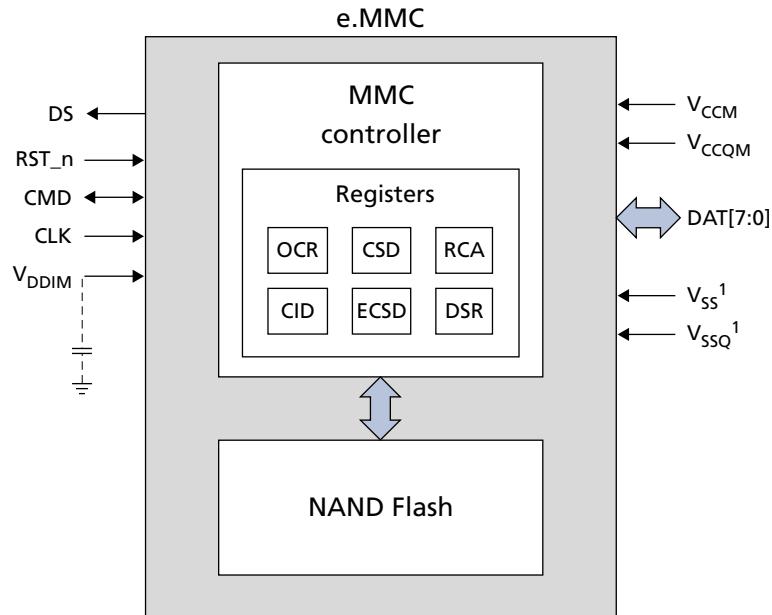


Notes: 1. Dimensions are in millimeters.

2. Solder ball composition: SAC302 with NiAu pads (96.8% Sn, 3.0% Ag, 0.2% Cu)

## Architecture

**Figure 7: e.MMC Functional Block Diagram**



Note: 1. V<sub>SS</sub> and V<sub>SSQ</sub> are internally connected.

## MMC Protocol Independent of NAND Flash Technology

The MMC specification defines the communication protocol between a host and a device. The protocol is independent of the NAND flash features included in the device. The device has an intelligent on-board controller that manages the MMC communication protocol.

The controller also handles block management functions such as logical block allocation and wear leveling. These management functions require complex algorithms and depend entirely on NAND flash technology (generation or memory cell type). The device handles these management functions internally, making them invisible to the host processor.

## Defect and Error Management

Micron e.MMC incorporates advanced technology for defect and error management. If a defective block is identified, the device completely replaces it with a spare block. This process is invisible to the host and does not affect user-allocated data space.

The device also includes a built-in error correction code (ECC) algorithm to ensure data integrity is maintained. To best implement these advanced technologies and ensure proper data loading and storage over the life of the device, the host must follow these precautions:

- Check the status after WRITE, READ, and ERASE operations.
- Avoid power-down during WRITE and ERASE operations.

As best practice, Micron recommends the usage of Power Off Notification (PON) and refresh mechanism.



## OCR Register

The 32-bit operation conditions register (OCR) stores the voltage profile of the card and the access mode indication. In addition, this register includes a status information bit.

**Table 7: OCR Parameters**

| OCR Bits | OCR Value                         | Description                |
|----------|-----------------------------------|----------------------------|
| [31]     | 1b (ready)/0b (busy) <sup>1</sup> | Device power-on status bit |
| [30:29]  | 10b                               | Sector mode                |
| [28:24]  | 0 0000b                           | Reserved                   |
| [23:15]  | 1 1111 1111b                      | 2.7–3.6V voltage range     |
| [14:8]   | 000 0000b                         | 2.0–2.7V voltage range     |
| [7]      | 1b                                | 1.70–1.95V voltage range   |
| [6:0]    | 000 0000b                         | Reserved                   |

Note: 1. OCR = C0FF8080h after the device has completed power-up.



## CID Register

The card identification (CID) register is 128 bits wide. It contains the device identification information used during the card identification phase as required by e.MMC protocol. Each device is created with a unique identification number.

**Table 8: CID Register Field Parameters**

| Name                  | Field | Width | CID Bits  | CID Value   |
|-----------------------|-------|-------|-----------|---|
| Manufacturer ID       | MID   | 8     | [127:120] | 13h   |
| Reserved              | –     | 6     | [119:114] | –   |
| Card/BGA              | CBX   | 2     | [113:112] | 01h   |
| OEM/application ID    | OID   | 8     | [111:104] | –   |
| Product name          | PNM   | 48    | [103:56]  | 8GB: 53304A333541h<br>(S0J35A)<br>16GB: 53304A353658h<br>(S0J56X)<br>32GB: 53304A353758h<br>(S0J57X)<br>64GB: 53304a353858h<br>(S0J58X)<br>128GB: 53304a353958h<br>(S0J59X) |
| Product revision      | PRV   | 8     | [55:48]   | –   |
| Product serial number | PSN   | 32    | [47:16]   | –   |
| Manufacturing date    | MDT   | 8     | [15:8]    | –   |
| CRC7 checksum         | CRC   | 7     | [7:1]     | –   |
| Not used; always 1    | –     | 1     | [0]       | –   |



## CSD Register

The card-specific data (CSD) register provides information about accessing the device contents. The CSD register defines the data format, error correction type, maximum data access time, and data transfer speed, as well as whether the DS register can be used. The programmable part of the register (entries marked with W or E in the following table) can be changed by the PROGRAM\_CSD (CMD27) command.

**Table 9: CSD Register Field Parameters**

| Name   | Field             | Density | Size (Bits) | Cell Type <sup>1</sup> | CSD Bits  | CSD Value |
|--|-------------------|---------|-------------|------------------------|-----------|-----------|
| CSD structure                                      | CSD_STRUCTURE     | –       | 2           | R                      | [127:126] | 3h        |
| System specification version                       | SPEC_VERS         | –       | 4           | R                      | [125:122] | 4h        |
| Reserved <sup>2</sup>                              | –                 | –       | 2           | R                      | [121:120] | –         |
| Data read access time 1                            | TAAC              | –       | 8           | R                      | [119:112] | 7Fh       |
| Data read access time 2 in CLK cycles (NSAC × 100) | NSAC              | –       | 8           | R                      | [111:104] | 01h       |
| Maximum bus clock frequency                        | TRAN_SPEED        | –       | 8           | R                      | [103:96]  | 32h       |
| Card command classes                               | CCC               | –       | 12          | R                      | [95:84]   | 8F5h      |
| Maximum read data block length                     | READ_BL_LEN       | –       | 4           | R                      | [83:80]   | 09h       |
| Partial blocks for reads supported                 | READ_BL_PARTIAL   | –       | 1           | R                      | [79]      | 0h        |
| Write block misalignment                           | WRITE_BL_MISALIGN | –       | 1           | R                      | [78]      | 0h        |
| Read block misalignment                            | READ_BL_MISALIGN  | –       | 1           | R                      | [77]      | 0h        |
| DSR implemented                                    | DSR_IMP           | –       | 1           | R                      | [76]      | 0h        |
| Reserved   | –                 | –       | 2           | R                      | [75:74]   | –         |
| Device size  | C_SIZE            | –       | 12          | R                      | [73:62]   | FFFh      |
| Maximum read current at $V_{DD,min}$               | VDD_R_CURR_MIN    | –       | 3           | R                      | [61:59]   | 0h        |
| Maximum read current at $V_{DD,max}$               | VDD_R_CURR_MAX    | –       | 3           | R                      | [58:56]   | 0h        |
| Maximum write current at $V_{DD,min}$              | VDD_W_CURR_MIN    | –       | 3           | R                      | [55:53]   | 0h        |
| Maximum write current at $V_{DD,max}$              | VDD_W_CURR_MAX    | –       | 3           | R                      | [52:50]   | 0h        |
| Device size multiplier                             | C_SIZE_MULT       | –       | 3           | R                      | [49:47]   | 7h        |
| Erase group size                                   | ERASE_GRP_SIZE    | –       | 5           | R                      | [46:42]   | 1Fh       |
| Erase group size multiplier                        | ERASE_GRP_MULT    | –       | 5           | R                      | [41:37]   | 1Fh       |
| Write protect group size                           | WP_GRP_SIZE       | –       | 5           | R                      | [36:32]   | 0Fh       |
| Write protect group enable                         | WP_GRP_ENABLE     | –       | 1           | R                      | [31]      | 1h        |
| Manufacturer default ECC                           | DEFAULT_ECC       | –       | 2           | R                      | [30:29]   | 0h        |
| Write-speed factor                                 | R2W_FACTOR        | –       | 3           | R                      | [28:26]   | 01h       |
| Maximum write data block length                    | WRITE_BL_LEN      | –       | 4           | R                      | [25:22]   | 09h       |

**Table 9: CSD Register Field Parameters (Continued)**

| Name                                | Field              | Density | Size (Bits) | Cell Type <sup>1</sup> | CSD Bits | CSD Value |
|-------------------------------------|--------------------|---------|-------------|------------------------|----------|-----------|
| Partial blocks for writes supported | WRITE_BL_PARTIAL   | –       | 1           | R                      | [21]     | 0h        |
| Reserved                            | –                  | –       | 4           | R                      | [20:17]  | –         |
| Content protection application      | CONTENT_PROT_APP   | –       | 1           | R                      | [16]     | 0h        |
| File-format group                   | FILE_FORMAT_GRP    | –       | 1           | R/W                    | [15]     | 0h        |
| Copy flag (OTP)                     | COPY               | –       | 1           | R/W                    | [14]     | 0h        |
| Permanent write protection          | PERM_WRITE_PROTECT | –       | 1           | R/W                    | [13]     | 0h        |
| Temporary write protection          | TMP_WRITE_PROTECT  | –       | 1           | R/W/E                  | [12]     | 0h        |
| File format                         | FILE_FORMAT        | –       | 2           | R/W                    | [11:10]  | 0h        |
| ECC                                 | ECC                | –       | 2           | R/W/E                  | [9:8]    | 0h        |
| CRC                                 | CRC                | –       | 7           | R/W/E                  | [7:1]    | –         |
| Not used, always 1                  | –                  | –       | 1           | –                      | [0]      | –         |

Notes: 1. R = Read-only;

R/W = One-time programmable and readable;

R/W/E = Multiple writable with value kept after a power cycle, assertion of the RST\_n signal, and any CMD0 reset, and readable

2. Reserved bits should be read as 0.



## ECSD Register

The 512-byte extended card-specific data (ECSD) register defines device properties and selected modes. The most significant 320 bytes are the properties segment. This segment defines device capabilities and cannot be modified by the host. The lower 192 bytes are the modes segment. The modes segment defines the configuration in which the device is working. The host can change the properties of modes segments using the SWITCH command.

**Table 10: ECSD Register Field Parameters**

| Name  | Field                                     | Density | Size (Bytes) | Cell Type <sup>1</sup> | ECSD Bytes | ECSD Value |
|---|---|---------|--------------|------------------------|------------|------------|
| <b>Properties Segment</b>                       |   |         |              |                        |            |            |
| Reserved <sup>2</sup>                           | –   | –       | 6            | TBD                    | [511:506]  | –          |
| Extended security error support                 | EXT_SECURITY_ERR                          | –       | 1            | R                      | [505]      | 00h        |
| Supported command sets                          | S_CMD_SET                                 | –       | 1            | R                      | [504]      | 01h        |
| HPI features                                    | HPI_FEATURES                              | –       | 1            | R                      | [503]      | 01h        |
| Background operations support                   | BKOPS_SUPPORT                             | –       | 1            | R                      | [502]      | 01h        |
| Max-packed READ commands                        | MAX_PACKED_READS                          | –       | 1            | R                      | [501]      | 00h        |
| Max-packed WRITE commands                       | MAX_PACKED_WRITES                         | –       | 1            | R                      | [500]      | 00h        |
| Data tag support                                | DATA_TAG_SUPPORT                          | –       | 1            | R                      | [499]      | 01h        |
| Tag unit size                                   | TAG_UNIT_SIZE                             | –       | 1            | R                      | [498]      | 03h        |
| Tag resources size                              | TAG_RES_SIZE                              | –       | 1            | R                      | [497]      | 00h        |
| Context management capabilities                 | CONTEXT_CAPABILITIES                      | –       | 1            | R                      | [496]      | 05h        |
| Large unit size                                 | LARGE_UNIT_SIZE_M1                        | –       | 1            | R                      | [495]      | 03h        |
| Extended partitions attribute support           | EXT_SUPPORT                               | –       | 1            | R                      | [494]      | 03h        |
| Supported modes                                 | SUPPORTED_MODES                           | –       | 1            | R                      | [493]      | 01h        |
| Field firmware update features                  | FFU_FEATURES                              | –       | 1            | R                      | [492]      | 00h        |
| Operation code timeout                          | OPERATION_CODE_TIMEOUT                    | –       | 1            | R                      | [491]      | 00h        |
| Field firmware update arguments                 | FFU_ARG                                   | –       | 4            | R                      | [490:487]  | 0000FFFFh  |
| Barrier support                                 | BARRIER_SUPPORT                           | –       | 1            | R                      | [486]      | 01h        |
| Reserved  | –   | –       | 177          | TBD                    | [485:309]  | –          |
| CMD queuing support                             | CMDQ_SUPPORT                              | –       | 1            | R                      | [308]      | 01h        |
| CMD queuing depth                               | CMDQ_DEPTH                                | –       | 1            | R                      | [307]      | 1Fh        |
| Reserved  | –   | –       | 1            | TBD                    | [306]      | –          |
| Number of firmware sectors correctly programmed | NUMBER_OF_FW_SECTORS_CORRECTLY_PROGRAMMED | –       | 4            | R                      | [305:302]  | 00h        |

**Table 10: ECSD Register Field Parameters (Continued)**

| Name  | Field                             | Density | Size (Bytes) | Cell Type <sup>1</sup> | ECSD Bytes | ECSD Value |
|---|-----------------------------------|---------|--------------|------------------------|------------|------------|
| Vendor proprietary health report  | VENDOR_PROPRI-ETARY_HEALTH_REPORT | –       | 32           | R                      | [301:270]  | 00h        |
| Device life time estimate type B  | DEVICE_LIFE_TIME_EST_TYP_B        | –       | 1            | R                      | [269]      | 01h        |
| Device life time estimate type A  | DEVICE_LIFE_TIME_EST_TYP_A        | –       | 1            | R                      | [268]      | 01h        |
| Pre-end of life information   | PRE_EOL_INFO                      | –       | 1            | R                      | [267]      | 01h        |
| Optimal read size   | OPTIMAL_READ_SIZE                 | –       | 1            | R                      | [266]      | 00h        |
| Optimal write size  | OPTIMAL_WRITE_SIZE                | –       | 1            | R                      | [265]      | 40h        |
| Optimal trim unit size  | OPTIMAL_TRIM_UNIT_SIZE            | –       | 1            | R                      | [264]      | 00h        |
| Device version  | DEVICE_VERSION                    | –       | 2            | R                      | [263:262]  | 0000h      |
| Firmware version  | FIRMWARE_VERSION                  | –       | 8            | R                      | [261:254]  | –          |
| Power class for 200 MHz DDR at V <sub>CC</sub> = 3.6V                     | PWR_CL_DDR_200_360                | –       | 1            | R                      | [253]      | 00h        |
| Cache size  | CACHE_SIZE                        | 8GB     | 4            | R                      | [252:249]  | 00000200h  |
|   |                                   | 16GB    |              |                        |            | 00000400h  |
|   |                                   | 32GB    |              |                        |            | 00000800h  |
|   |                                   | 64GB    |              |                        |            |            |
|   |                                   | 128GB   |              |                        |            |            |
| Generic CMD6 timeout  | GENERIC_CMD6_TIME                 | –       | 1            | R                      | [248]      | 0Ah        |
| Power-off notification (long) timeout                                     | POWER_OFF_LONG_TIME               | –       | 1            | R                      | [247]      | 32h        |
| Background operations status  | BKOPS_STATUS                      | –       | 1            | R                      | [246]      | 00h        |
| Number of correctly programmed sectors                                    | CORRECTLY_PROG_SECTORS_NUM        | –       | 4            | R                      | [245:242]  | 00000000h  |
| First initialization time after partitioning (first CMD1 to device ready) | INI_TIMEOUT_AP                    | –       | 1            | R                      | [241]      | 0Ah        |
| Cache flushing policy   | CACHE_FLUSH_POLICY                | –       | 1            | R                      | [240]      | 01h        |
| Power class for 52 MHz, DDR at 3.6V                                       | PWR_CL_DDR_52_360                 | –       | 1            | R                      | [239]      | 00h        |
| Power class for 52 MHz, DDR at 1.95V                                      | PWR_CL_DDR_52_195                 | –       | 1            | R                      | [238]      | 00h        |
| Power class for 200 MHz at 1.95V  | PWR_CL_200_195                    | –       | 1            | R                      | [237]      | 00h        |
| Power class for 200 MHz, at 1.3V  | PWR_CL_200_130                    | –       | 1            | R                      | [236]      | 00h        |

**Table 10: ECSD Register Field Parameters (Continued)**

| Name  | Field                              | Density                              | Size (Bytes) | Cell Type <sup>1</sup> | ECSD Bytes | ECSD Value |
|---|------------------------------------|--------------------------------------|--------------|------------------------|------------|------------|
| Minimum write performance for 8-bit at 52 MHz in DDR mode | MIN_PERF_DDR_W_8_52                | –                                    | 1            | R                      | [235]      | 00h        |
| Minimum read performance for 8-bit at 52 MHz in DDR mode  | MIN_PERF_DDR_R_8_52                | –                                    | 1            | R                      | [234]      | 00h        |
| Reserved  | –                                  | –                                    | 1            | TBD                    | [233]      | –          |
| TRIM multiplier   | TRIM_MULT                          | –                                    | 1            | R                      | [232]      | 01h        |
| Secure feature support                                    | SEC_FEATURE_SUPPORT                | –                                    | 1            | R                      | [231]      | 51h        |
| Secure erase multiplier                                   | SEC_ERASE_MULT                     | –                                    | 1            | R                      | [230]      | 01h        |
| Secure trim multiplier                                    | SEC_TRIM_MULT                      | –                                    | 1            | R                      | [229]      | 01h        |
| Boot information  | BOOT_INFO                          | –                                    | 1            | R                      | [228]      | 07h        |
| Reserved  | –                                  | –                                    | 1            | TBD                    | [227]      | –          |
| Boot partition size <sup>3</sup>                          | BOOT_SIZE_MULT                     | –                                    | 1            | R                      | [226]      | FCh        |
| Access size   | ACC_SIZE                           | –                                    | 1            | R                      | [225]      | 00h        |
| High-capacity erase unit size                             | HC_ERASE_GRP_SIZE                  | –                                    | 1            | R                      | [224]      | 01h        |
| High-capacity erase timeout                               | ERASE_TIMEOUT_MULT                 | –                                    | 1            | R                      | [223]      | 01h        |
| Reliable write-sector count                               | REL_WR_SEC_C                       | –                                    | 1            | R                      | [222]      | 01h        |
| High-capacity write protect group size                    | HC_WP_GRP_SIZE                     | 8GB<br>16GB<br>32GB<br>64GB<br>128GB | 1            | R                      | [221]      | 10h        |
| Sleep current (V <sub>CC</sub> )                          | S_C_VCC                            |                                      |              |                        |            | 20h        |
| Sleep current (V <sub>CCQ</sub> )                         | S_C_VCCQ                           |                                      |              |                        |            | 40h        |
| Production state awareness timeout                        | PRODUCTION_STATE_AWARENESS_TIMEOUT |                                      |              |                        |            | 00h        |
| Sleep/awake timeout                                       | S_A_TIMEOUT                        |                                      |              |                        |            | 00h        |
| Sleep notification timeout                                | SLEEP_NOTIFICATION_TIME            | –                                    | 1            | R                      | [217]      | 14h        |
| Sector count  | SEC_COUNT                          | 8GB<br>16GB<br>32GB<br>64GB<br>128GB | 4            | R                      | [215:212]  | 00E90000h  |
| Secure write protect information                          | SECURE_WP_INFO                     |                                      |              |                        |            | 01DA4000h  |
|   |                                    |                                      |              |                        |            | 03B48000h  |
|   |                                    |                                      |              |                        |            | 07690000h  |
|   |                                    |                                      |              |                        |            | 0ED20000h  |

**Table 10: ECSD Register Field Parameters (Continued)**

| Name  | Field                 | Density | Size (Bytes) | Cell Type <sup>1</sup> | ECSD Bytes | ECSD Value |
|---|-----------------------|---------|--------------|------------------------|------------|------------|
| Minimum write performance for 8-bit at 52 MHz                     | MIN_PERF_W_8_52       | –       | 1            | R                      | [210]      | 00h        |
| Minimum read performance for 8-bit at 52 MHz                      | MIN_PERF_R_8_52       | –       | 1            | R                      | [209]      | 00h        |
| Minimum write performance for 8-bit at 26 MHz and 4-bit at 52 MHz | MIN_PERF_W_8_26_4_52  | –       | 1            | R                      | [208]      | 00h        |
| Minimum read performance for 8-bit at 26 MHz and 4-bit at 52 MHz  | MIN_PERF_R_8_26_4_52  | –       | 1            | R                      | [207]      | 00h        |
| Minimum write performance for 4-bit at 26 MHz                     | MIN_PERF_W_4_26       | –       | 1            | R                      | [206]      | 00h        |
| Minimum read performance for 4-bit at 26 MHz                      | MIN_PERF_R_4_26       | –       | 1            | R                      | [205]      | 00h        |
| Reserved  | –                     | –       | 1            | TBD                    | [204]      | –          |
| Power class for 26 MHz at 3.6V                                    | PWR_CL_26_360         | –       | 1            | R                      | [203]      | 00h        |
| Power class for 52 MHz at 3.6V                                    | PWR_CL_52_360         | –       | 1            | R                      | [202]      | 00h        |
| Power class for 26 MHz at 1.95V                                   | PWR_CL_26_195         | –       | 1            | R                      | [201]      | 00h        |
| Power class for 52 MHz at 1.95V                                   | PWR_CL_52_195         | –       | 1            | R                      | [200]      | 00h        |
| Partition switching timing  | PARTITION_SWITCH_TIME | –       | 1            | R                      | [199]      | 01h        |
| Out-of-interrupt busy timing                                      | OUT_OF_INTERRUPT_TIME | –       | 1            | R                      | [198]      | 0Fh        |
| I/O driver strength   | DRIVER_STRENGTH       | –       | 1            | R                      | [197]      | 1Fh        |
| Device type   | DEVICE_TYPE           | –       | 1            | R                      | [196]      | 57h        |
| Reserved  | –                     | –       | 1            | TBD                    | [195]      | –          |
| CSD structure version   | CSD_STRUCTURE         | –       | 1            | R                      | [194]      | 02h        |
| Reserved  | –                     | –       | 1            | TBD                    | [193]      | –          |
| Extended CSD revision   | EXT_CSD_REV           | –       | 1            | R                      | [192]      | 08h        |
| <b>Modes Segment</b>  |                       |         |              |                        |            |            |
| Command set   | CMD_SET               | –       | 1            | R/W/E_P                | [191]      | 00h        |
| Reserved  | –                     | –       | 1            | TBD                    | [190]      | –          |
| Command set revision  | CMD_SET_REV           | –       | 1            | R                      | [189]      | 00h        |
| Reserved  | –                     | –       | 1            | TBD                    | [188]      | –          |
| Power class   | POWER_CLASS           | –       | 1            | R/W/E_P                | [187]      | 00h        |
| Reserved  | –                     | –       | 1            | TBD                    | [186]      | –          |
| High-speed interface timing                                       | HS_TIMING             | –       | 1            | R/W/E_P                | [185]      | 00h        |



Table 10: ECSD Register Field Parameters (Continued)

| Name   | Field                | Density | Size (Bytes) | Cell Type <sup>1</sup>      | ECSD Bytes | ECSD Value |
|--|----------------------|---------|--------------|-----------------------------|------------|------------|
| Strobe support   | STROBE_SUPPORT       | –       | 1            | R                           | [184]      | 00h        |
| Bus width mode   | BUS_WIDTH            | –       | 1            | W/E_P                       | [183]      | 00h        |
| Reserved   | –                    | –       | 1            | TBD                         | [182]      | –          |
| Erased memory content  | ERASED_MEM_CONT      | –       | 1            | R                           | [181]      | 00h        |
| Reserved   | –                    | –       | 1            | TBD                         | [180]      | –          |
| Partition configuration  | PARTITION_CONFIG     | –       | 1            | R/W/E,<br>R/W/E_P           | [179]      | 00h        |
| Boot configuration protection  | BOOT_CONFIG_PROT     | –       | 1            | R/W,<br>R/W/C_P             | [178]      | 00h        |
| Boot bus conditions  | BOOT_BUS_CONDITIONS  | –       | 1            | R/W/E                       | [177]      | 00h        |
| Reserved   | –                    | –       | 1            | TBD                         | [176]      | –          |
| High-density erase group definition  | ERASE_GROUP_DEF      | –       | 1            | R/W/E_P                     | [175]      | 00h        |
| Boot write protection status registers   | BOOT_WP_STATUS       | –       | 1            | R                           | [174]      | 00h        |
| Boot area write protection register  | BOOT_WP              | –       | 1            | R/W,<br>R/W/C_P             | [173]      | 00h        |
| Reserved   | –                    | –       | 1            | TBD                         | [172]      | –          |
| User write protection register   | USER_WP              | –       | 1            | R/W,<br>R/W/C_P,<br>R/W/E_P | [171]      | 00h        |
| Reserved   | –                    | –       | 1            | TBD                         | [170]      | –          |
| Firmware configuration   | FW_CONFIG            | –       | 1            | R/W                         | [169]      | 00h        |
| RPMB size  | RPMB_SIZE_MULT       | –       | 1            | R                           | [168]      | 20h        |
| Write reliability setting register <sup>4</sup> Write reliability parameter register | WR_REL_SET           | –       | 1            | R/W                         | [167]      | 1Fh        |
| WR_REL_PARAM   | WR_REL_PARAM         | –       | 1            | R                           | [166]      | 15h        |
|  |                      |         |              |                             |            |            |
| SANITIZE START operation   | SANITIZE_START       | –       | 1            | W/E_P                       | [165]      | 00h        |
| Manually start background operations   | BKOPS_START          | –       | 1            | W/E_P                       | [164]      | 00h        |
| Enable background operations handshake   | BKOPS_EN             | –       | 1            | R/W,<br>R/W/E               | [163]      | 00h        |
| Hardware reset function  | RST_n_FUNCTION       | –       | 1            | R/W                         | [162]      | 00h        |
| HPI management   | HPI_MGMT             | –       | 1            | R/W/E_P                     | [161]      | 00h        |
| Partitioning support   | PARTITIONING_SUPPORT | –       | 1            | R                           | [160]      | 07h        |
| Maximum enhanced area size   | MAX_ENH_SIZE_MULT    | 8GB     | 3            | R                           | [159:157]  | 0001C9h    |
|  |                      | 16GB    |              |                             |            | 0003ABh    |
|  |                      | 32GB    |              |                             |            | 000760h    |
|  |                      | 64GB    |              |                             |            | 000764h    |
|  |                      | 128GB   |              |                             |            | 000766h    |

**Table 10: ECSD Register Field Parameters (Continued)**

| Name   | Field                       | Density | Size (Bytes) | Cell Type <sup>1</sup> | ECSD Bytes | ECSD Value |
|--|-----------------------------|---------|--------------|------------------------|------------|------------|
| Partitions attribute                                     | PARTITIONS_ATTRIBUTE        | –       | 1            | R/W                    | [156]      | 00h        |
| Partitioning setting                                     | PARTITION_SETTING_COMPLETED | –       | 1            | R/W                    | [155]      | 00h        |
| General-purpose partition size                           | GP_SIZE_MULT                | –       | 12           | R/W                    | [154:143]  | 00h        |
| Enhanced user data area size                             | ENH_SIZE_MULT               | –       | 3            | R/W                    | [142:140]  | 000000h    |
| Enhanced user data start address                         | ENH_START_ADDR              | –       | 4            | R/W                    | [139:136]  | 00000000h  |
| Reserved   | –                           | –       | 1            | TBD                    | [135]      | –          |
| Bad block management mode                                | SEC_BAD_BLK_MGMNT           | –       | 1            | R/W                    | [134]      | 00h        |
| Production state awareness                               | PRODUCTION_STATE_AWARENESS  | –       | 1            | R/W/E                  | [133]      | 00h        |
| Package case temperature is controlled                   | TCASE_SUPPORT               | –       | 1            | W/E_P                  | [132]      | 00h        |
| Periodic wake-up   | PERIODIC_WAKEUP             | –       | 1            | R/W/E                  | [131]      | 00h        |
| Program CID/CSD in DDR mode support                      | PROGRAM_CID_CSD_DDR_SUPPORT | –       | 1            | R                      | [130]      | 01h        |
| Reserved   | –                           | –       | 2            | TBD                    | [129:128]  | –          |
| Vendor specific fields                                   | VENDOR_SPECIFIC_FIELD       | –       | 64           | <vendor specific>      | [127:64]   | –          |
| Native sector size                                       | NATIVE_SECTOR_SIZE          | –       | 1            | R                      | [63]       | 00h        |
| Sector size emulation                                    | USE_NATIVE_SECTOR           | –       | 1            | R/W                    | [62]       | 00h        |
| Sector size  | DATA_SECTOR_SIZE            | –       | 1            | R                      | [61]       | 00h        |
| 1st initialization after disabling sector size emulation | INI_TIMEOUT_EMU             | –       | 1            | R                      | [60]       | 00h        |
| Class 6 commands control                                 | CLASS_6_CTRL                | –       | 1            | R/W/E_P                | [59]       | 00h        |
| Number of addressed group to be released                 | DYNCAP_NEEDED               | –       | 1            | R                      | [58]       | 00h        |
| Exception events control                                 | EXCEPTION_EVENTS_CTRL       | –       | 2            | R/W/E_P                | [57:56]    | 0000h      |
| Exception events status                                  | EXCEPTION_EVENTS_STATUS     | –       | 2            | R                      | [55:54]    | 0000h      |
| Extended partitions attribute                            | EXT_PARTITIONS_ATTRIBUTE    | –       | 2            | R/W                    | [53:52]    | 0000h      |
| Context configuration                                    | CONTEXT_CONF                | –       | 15           | R/W/E_P                | [51:37]    | 00h        |
| Packed command status                                    | PACKED_COMMAND_STATUS       | –       | 1            | R                      | [36]       | 00h        |
| Packed command failure index                             | PACKED_FAILURE_INDEX        | –       | 1            | R                      | [35]       | 00h        |
| Power-off notification                                   | POWER_OFF_NOTIFICATION      | –       | 1            | R/W/E_P                | [34]       | 00h        |
| Control to turn the cache on/off                         | CACHE_CTRL                  | –       | 1            | R/W/E_P                | [33]       | 00h        |

**Table 10: ECSD Register Field Parameters (Continued)**

| Name                               | Field                              | Density | Size (Bytes) | Cell Type <sup>1</sup> | ECSD Bytes | ECSD Value |
|------------------------------------|------------------------------------|---------|--------------|------------------------|------------|------------|
| Flushing of the cache              | FLUSH_CACHE                        | –       | 1            | W/E_P                  | [32]       | 00h        |
| Control to turn the barrier on/off | BARRIER_CTRL                       | –       | 1            | R/W                    | [31]       | 00h        |
| Mode configuration                 | MODE_CONFIG                        | –       | 1            | R/W/E_P                | [30]       | 00h        |
| Mode operation codes               | MODE_OPERATION_CODES               | –       | 1            | W/E_P                  | [29]       | 00h        |
| Reserved                           | –                                  | –       | 2            | TBD                    | [28:27]    | –          |
| Field firmware update status       | FFU_STATUS                         | –       | 1            | R                      | [26]       | 00h        |
| Pre-loading data size              | PRE_LOADING_DATA_SIZE              | –       | 4            | R/W/E_P                | [25:22]    | 00h        |
| Maximum pre-loading data size      | MAX_PRE_LOADING_DATA_SIZE          | 8GB     | 4            | R                      | [21:18]    | 005D3310h  |
|                                    |                                    | 16GB    |              |                        |            | 00BDB320h  |
|                                    |                                    | 32GB    |              |                        |            | 017B6640h  |
|                                    |                                    | 64GB    |              |                        |            | 02F6CCA8h  |
|                                    |                                    | 128GB   |              |                        |            | 05ED9978h  |
| Product state awareness enablement | PRODUCT_STATE_AWARENESS_ENABLEMENT | –       | 1            | R/W/E&R                | [17]       | 03h        |
| Secure removal type                | SECURE_REMOVAL_TYPE                | –       | 1            | R/W&R                  | [16]       | 01h        |
| Command queue mode enable          | CMDQ_MODE_EN                       | –       | 1            | R/W/E_P                | [15]       | 00h        |
| Reserved                           | –                                  | –       | 15           | TBD                    | [14:0]     | –          |

Notes: 1. R = Read-only;

R/W = One-time programmable and readable;

R/W/E = Multiple writable with the value kept after a power cycle, assertion of the RST\_n signal, and any CMD0 reset, and readable;

R/W/C\_P = Writable after the value is cleared by a power cycle and assertion of the RST\_n signal (the value not cleared by CMD0 reset) and readable;

R/W/E\_P = Multiple writable with the value reset after a power cycle, assertion of the RST\_n signal, and any CMD0 reset, and readable;

W/E\_P = Multiple writable with the value reset after power cycle, assertion of the RST\_n signal, and any CMD0 reset, and not readable

2. Reserved bits should be read as 0.

3. Boot partition size is configurable by host. Refer to local Micron support for information.

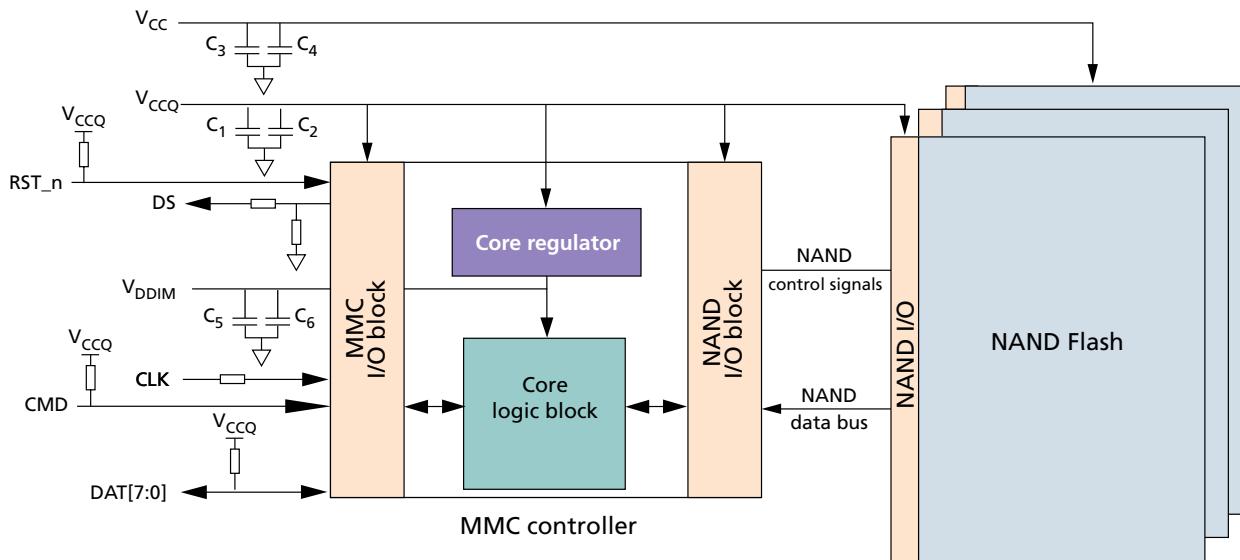
4. Micron has tested power failure under best-application knowledge conditions with positive results. Customers may request a dedicated test for their specific application condition. Micron set this register during factory test and used the one-time programming option.

## DC Electrical Specifications – Device Power

The device current consumption for various device configurations is defined in the power class fields of the ECSD register.

$V_{CC}$  is used for the NAND Flash device and its interface voltage;  $V_{CCQ}$  is used for the controller and the e.MMC interface voltage.

**Figure 8: Device Power Diagram**



**Table 11: Absolute Maximum Ratings**

| Parameters       | Symbol    | Min  | Max | Unit |
|------------------|-----------|------|-----|------|
| Voltage input    | $V_{IN}$  | -0.6 | 4.6 | V    |
| $V_{CC}$ supply  | $V_{CC}$  | -0.6 | 4.6 | V    |
| $V_{CCQ}$ supply | $V_{CCQ}$ | -0.6 | 4.6 | V    |

Notes: 1. Voltage on any pin relative to  $V_{SS}$ .

**Table 12: Temperature Grade**

| Temperature Grade | Condition | Ambient Temperature - $T_a$ | Max $T_{case}$ | Unit |
|-------------------|-----------|-----------------------------|----------------|------|
| AIT               | Operating | -40 to 85                   | 95             | °C   |
|                   | Storage   |                             |                |      |
| AAT               | Operating | -40 to 105                  | 115            | °C   |
|                   | Storage   |                             |                |      |

**Table 13: Capacitor and Resistance Specifications**

| Parameter                                       | Symbol  | Min | Max  | Typ | Units | Notes |
|---|---------|-----|------|-----|-------|-------|
| Pull-up resistance: CMD                         | R_CMD   | 4.7 | 50   | 10  | kΩ    | 1     |
| Pull-up resistance: DAT[7:0]                    | R_DAT   | 10  | 50   | 50  | kΩ    | 1     |
| Pull-up resistance: RST_n                       | R_RST_n | 4.7 | 50   | 50  | kΩ    | 2     |
| CLK/CMD/DS/DAT[7:0] impedance                   |         | 45  | 55   | 50  | Ω     | 3     |
| Serial resistance on CLK                        | SR_CLK  | 0   | 47   | 22  | Ω     |       |
| Serial resistance on DS                         | SR_DS   | 0   | 47   | 22  | Ω     | 4     |
| Pull-down resistance: DS                        | R_DS    | 10  | 100  | –   | kΩ    |       |
| V <sub>CCQ</sub> capacitor                      | C1      | 2.2 | 4.7  | 2.2 | μF    | 5     |
|   | C2      | 0.1 | 0.22 | 0.1 |       |       |
| V <sub>CC</sub> capacitor                       | C3      | 2.2 | 4.7  | 2.2 | μF    | 6     |
|   | C4      | 0.1 | 0.22 | 0.1 |       |       |
| V <sub>DDIM</sub> capacitor (C <sub>reg</sub> ) | C5      | 1   | 4.7  | 1   | μF    | 7     |
|   | C6      | 0.1 | 0.1  | 0.1 |       |       |

Notes:

1. Used to prevent bus floating.
2. If host does not use H/W RESET (RST\_n), pull-up resistance is not needed on RST\_n line (Extended\_CSD[162] = 00h).
3. Impedance match.
4. Recommended in order to compensate eventual impedance mismatch on the PCB.
5. The coupling capacitor should be connected with V<sub>CCQ</sub> and V<sub>SSQ</sub> as closely as possible.
6. The coupling capacitor should be connected with V<sub>CC</sub> and V<sub>SS</sub> as closely as possible.
7. The coupling capacitor should be connected with V<sub>DDIM</sub> and V<sub>SS</sub> as closely as possible.

## Product features

The list below shows the JEDEC features not supported. See the full JEDEC/MMC Standard No. 84-B51 available at [www.jedec.org/sites/default/files/docs/JESD84-B51.pdf](http://www.jedec.org/sites/default/files/docs/JESD84-B51.pdf)

- Packed CMDs
- Context ID/Data tag (this feature is implemented at the protocol level)
- Dynamic device capacity
- Thermal spec
- Large sector size - 4KB (<256GB)
- Large sector size - 4KB (≥256GB)
- Extended security protocol
- Secure erase/secure trim\*
- Forced erase\*

\* The feature implements as logical erase mode: It moves the mapped host address range to the unmapped host address range. When the operation is complete, the data still exists, but the mapped device address range behaves as if overwritten with all 0s.



## Revision History

### Rev. J – 12/2021

- Updated Signal Descriptions table
- Added note of the solder ball composition to package dimensions figures (code NA, BH, and NS)

### Rev. I – 11/2020

- Updated Temperature Grade table in DC Electrical Specifications – Device Power

### Rev. H – 02/2020

- Added Retention AEC-Q100-005 compliance and automotive grade documents

### Rev. G – 10/2018

- Updated Part Numbers status

### Rev. F – 08/2018

- Removed Preliminary header and updated Part Numbers status
- Updated current consumption tables
- Updated ECSD register [163], [133], [15]
- Corrected typo of JEDEC standard link

### Rev. E – 06/2018

- Updated ECSD register [184] to 00h
- Added Temperature Grade table in DC Electrical Specifications

### Rev. D – 02/2018

- Added Important Notes and Warnings section for further clarification aligning to industry standards
- Removed table of performance and current at DDR52
- Updated values of performance and current in related tables
- Updated values in CSD and ECSD registers

### Rev. C – 10/2017

- Added MPN 32GB 153b AAT to the list
- Added MPNs 8GB, 16GB, 64GB, 128GB 100/153b AIT/AAT to the list
- Added values in the ECSD register [308], [307], [240], [252:249], [211], [184], [21:18]
- Added list of non-supported features

### Rev. B – 07/2017

- Fixed package height dimension
- Fixed VSF numbering in Signal Descriptions table
- Corrected typo of SEC\_COUNT [215:212] value in ECSD Register Field Parameters table: Changed from 03BA8000h to 03B48000h



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**Rev. A – 06/2017**

- Initial release

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This data sheet contains minimum and maximum limits specified over the power supply and temperature range set forth herein. Although considered final, these specifications are subject to change, as further product development and data characterization sometimes occur.